

HQ:CSC37/tipless/AI BS

Tipless AFM Probe with 3 Different Contact Mode AFM Cantilevers

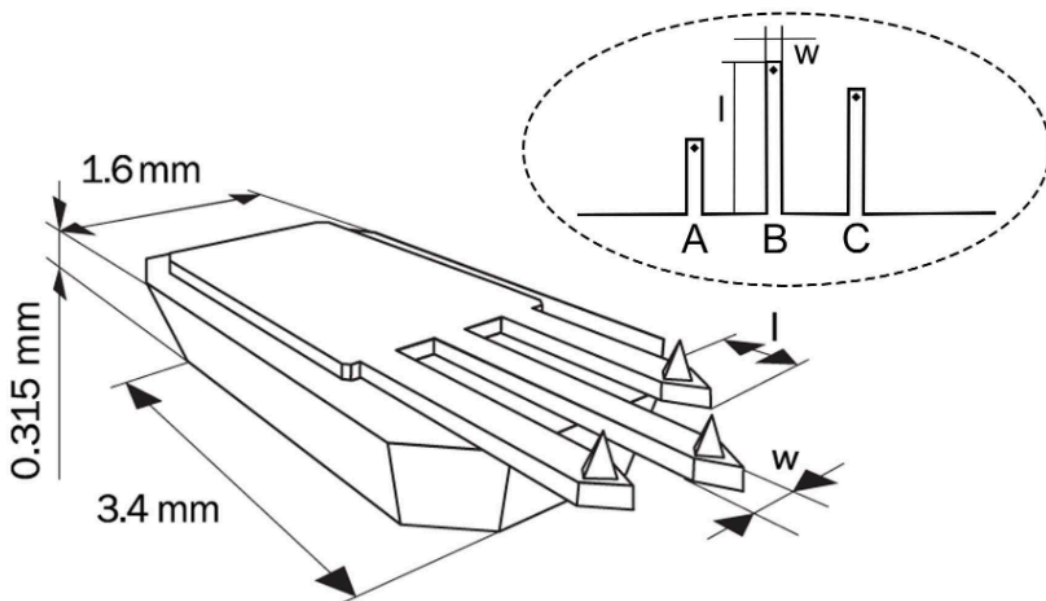
AFM probes of the HQ:CSC37 series have three different tipless contact mode AFM cantilevers on one side of the holder chip. They can be used in various applications.

The HQ AFM probes offer high consistency of the AFM tip radius, the AFM cantilever reflectivity and the quality factor.

The aluminum reflective coating enhances the laser reflectivity of the AFM cantilevers by approximately 2.5 times.

Coating

Reflective Aluminum



AFM Probe Specifications

AFM Tip

SHAPE
Tipless

AFM Cantilever

CANTILEVER	SHAPE	FORCE CONST.	RES. FREQ.	LENGTH	WIDTH	THICKNESS
Cantilever A	Beam	0.8 N/m (0.3 – 2 N/m)*	40 kHz (30 – 55 kHz)*	250 μm (1 – 255 μm)*	35 μm (32 – 38 μm)*	2 μm (1.5 – 2.5 μm)*
Cantilever B	Beam	0.3 N/m (0.1 – 0.6 N/m)*	20 kHz (15 – 30 kHz)*	350 μm (1 – 355 μm)*	35 μm (32 – 38 μm)*	2 μm (1.5 – 2.5 μm)*
Cantilever C	Beam	0.4 N/m (0.1 – 1 N/m)*	30 kHz (20 – 40 kHz)*	300 μm (1 – 305 μm)*	35 μm (32 – 38 μm)*	2 μm (1.5 – 2.5 μm)*

* typical values